

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NAGANAWA ET AL.	
		Examiner Zachary M. Pape	Art Unit 2835	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0008483	01-2004	Cheon, Kioan	361/687
*	B	US-6,313,990	11-2001	Cheon, Kioan	361/699
*	C	US-5,693,871	12-1997	Stout et al.	73/1.68
*	D	US-2005/0178528	08-2005	Ohashi et al.	165/080.3
*	E	US-2005/0180105	08-2005	Matsushima et al.	361/699
*	F	US-2005/0180107	08-2005	Naganawa et al.	361/699
G	US-				
H	US-				
I	US-				
J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.